

FDS8812NZ N-Channel PowerTrench[®] MOSFET 30V, 20A, 4.0m Ω

Features

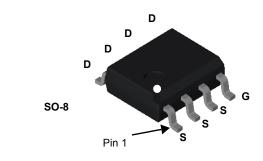
- Max $r_{DS(on)} = 4.0 m\Omega$ at V_{GS} = 10V, I_D = 20A
- Max $r_{DS(on)}$ = 4.9m Ω at V_{GS} = 4.5V, I_D =18A
- HBM ESD protection level of 6.4KV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- RoHS compliant

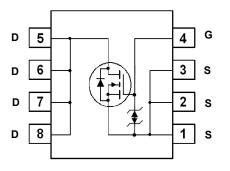


General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units V	
V _{DS}	Drain to Source Voltage	30			
V _{GS}	Gate to Source Voltage		±20	V	
ID	Drain Current -Continuous	(Note 1a)	20	Α	
	-Pulsed		80		
E _{AS}	Single Pulse Avalanche Energy	(Note 4)	661	mJ	
P _D	Power Dissipation	(Note 1a)	2.5	W	
	Power Dissipation	(Note 1b)	1.0		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	25	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	125	

Package Marking and Ordering Information

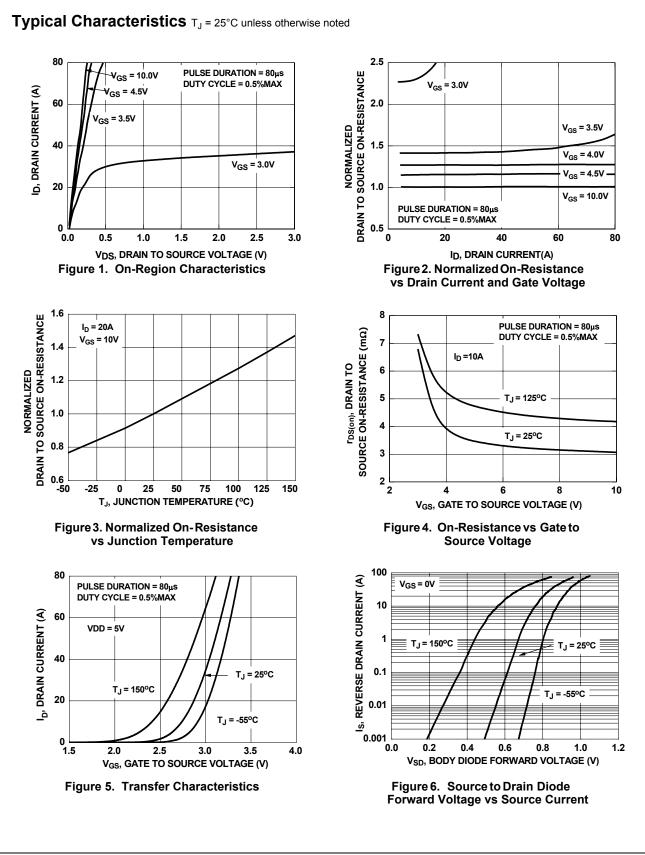
Device Marking	Device	Reel Size	Tape Width	Quantity
FDS8812NZ	FDS8812NZ	13"	12mm	2500 units

	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics			-		
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	30			V
ΔBV_{DSS} $\Delta T_{.1}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu$ A, referenced to 25°C		19		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V, V_{GS} = 0V$			1	μA
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±10	μA
	cteristics (Note 2)					
V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250μA	1	1.8	3	V
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage			1.0	0	
$\Delta V_{GS(th)}$ ΔT_{J}	Temperature Coefficient	$I_D = 250 \mu A$, referenced to $25^{\circ}C$		-7		mV/°C
-		V _{GS} = 10V, I _D = 20A		3.1	4.0	
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 4.5V, I _D = 18A		3.8	4.9	mΩ
		V_{GS} = 10V, I_D = 20A, T_J = 125°C		4.2	5.3	
9 _{FS}	Forward Transconductance	$V_{DS} = 5V, I_D = 20A$		87		S
-	Characteristics			1		1
C _{iss}	Input Capacitance	- V _{DS} = 15V, V _{GS} = 0V,		5205	6925	pF
C _{oss}	Output Capacitance	f = 1MHz		945	1260	pF
C _{rss}	Reverse Transfer Capacitance	6 4941		580	870	pF
R _g	Gate Resistance	f = 1MHz		1.5		Ω
Switching	g Characteristics					
t _{d(on)}	Turn-On Delay Time			18	33	ns
t _r	Rise Time	$V_{DD} = 15V, I_D = 20A$		13	24	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$		55	88	ns
t _f	Fall Time			12	22	ns
Q _g	Total Gate Charge	$V_{GS} = 0V$ to 10V $V_{DD} = 15V$		90	126	nC
Q _g	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$ $I_D = 20A$		49	69	nC
Q _{gs}	Gate to Source Charge			16		nC
Q _{gd}	Gate to Drain "Miller" Charge			18		nC
	rea Diada Characteriatica					1
	urce Diode Characteristics	$\lambda = 0 \lambda = 0.4$		0.7	4.0	M
	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 2.1A$ (Note 2)		0.7	1.2	V
V _{SD}	Deverse Decevery Time			36	54	ns
Drain-Soi V _{SD} t _{rr}	Reverse Recovery Time Reverse Recovery Charge	— I _F = 20A, di/dt = 100A/μs		33	50	nC

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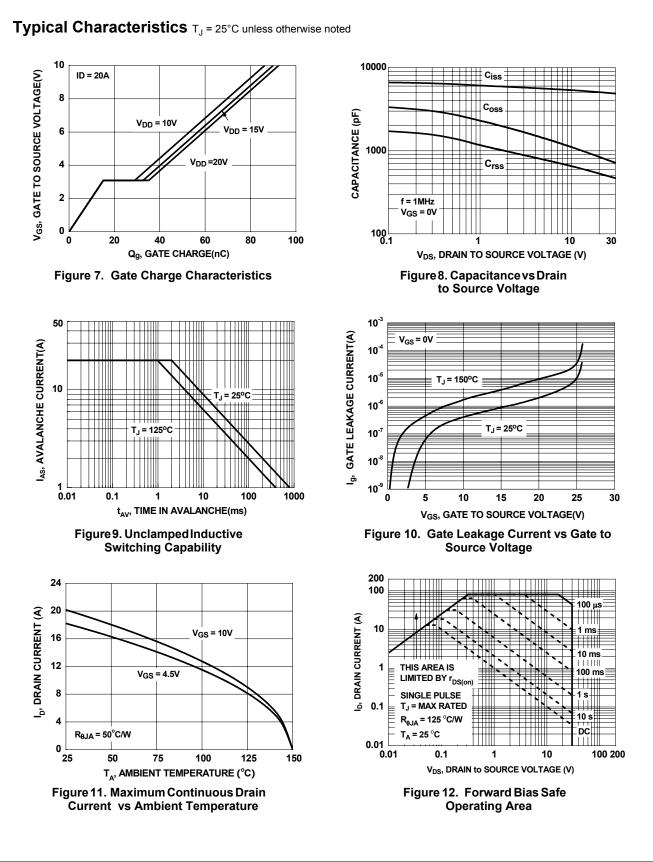
Pulse Test: Pulse Width < 300 us, Duty Cycle < 2%.
The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
Starting T_J = 25°C, L = 3mH, I_{AS} = 21A, V_{DD} = 30V, V_{GS} = 10V.

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FDS8812NZ Rev.C1

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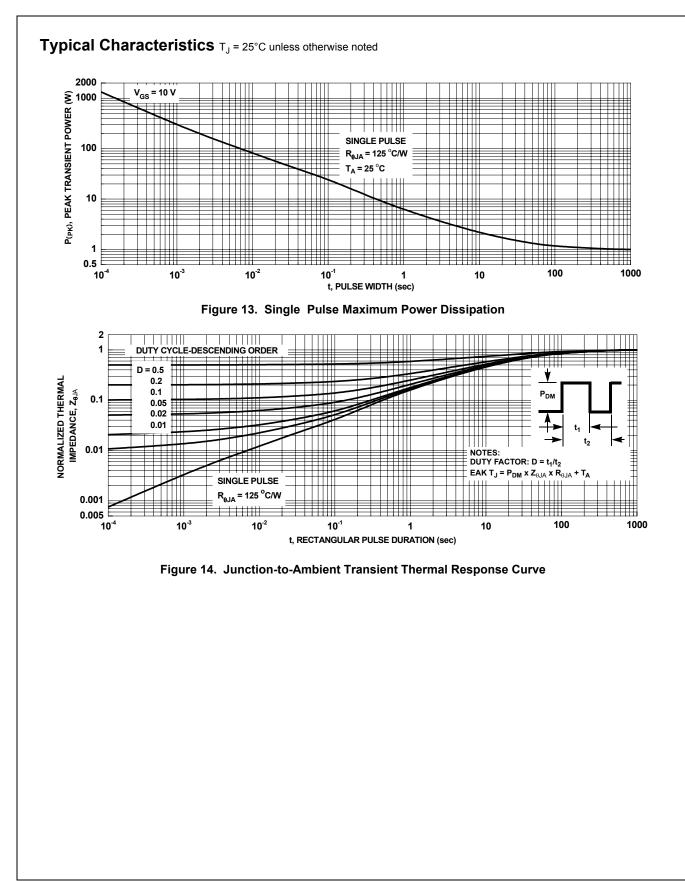


FDS8812NZ Rev.C1

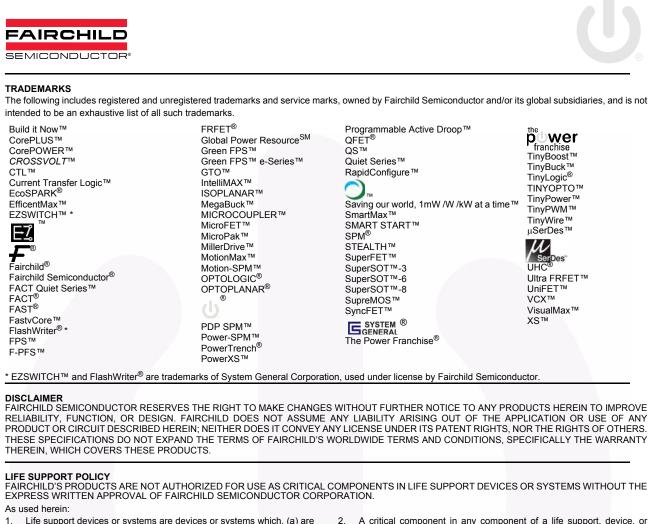
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- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

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